

**Search Notes**

Application/Control No.

10/615,229

Examiner

Y. Lee

Applicant(s)/Patent under  
Reexamination

ITOI ET AL.

Art Unit

2621

**SEARCHED**

Class	Subclass	Date	Examiner
375	240.26	4/25/2007	YL
348	48		
H04N	7/12		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR